


<b>Search Notes</b>  	<b>Application/Control No.</b>  10074117	<b>Applicant(s)/Patent Under Reexamination</b>  BUCHNER ET AL.
	<b>Examiner</b>  Son P. Huynh	<b>Art Unit</b>  2623

SEARCHED			
Class	Subclass	Date	Examiner
725	152-153, 112, 141-142, 89-90, 115	9/29/06	JM
386	33, 46	9/29/06	JM
725	78,80,131,133,139,141,151,153	3/30/07	AH
386	46,83	3/30/07	AH
	update search	10/16/07	AH
	update search	7/16/08	AH
725	78,80,82,68,71,100,131,133,139,141,151,153	7/16/08	AH

SEARCH NOTES			
Search Notes		Date	Examiner
EAST Search		9/29/06	JM
Spoke with Scott Beliveau and Chris Lambrecht		9/29/06	JM
East text searched enclosed		3/30/07	AH
Update East Text Search enclosed		10/16/07	AH
Update Text Search Enclosed		7/16/08	AH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner